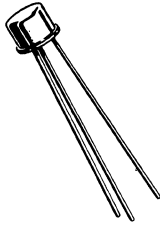


2N3883 (GERMANIUM)



Medium-current, germanium PNP high-speed switching transistor.

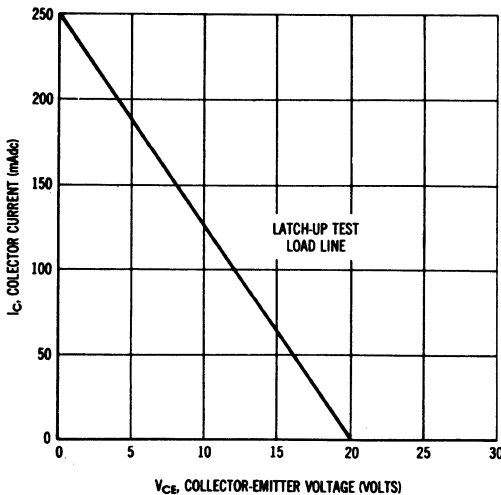
CASE 31 (TO-5)

Collector connected to case

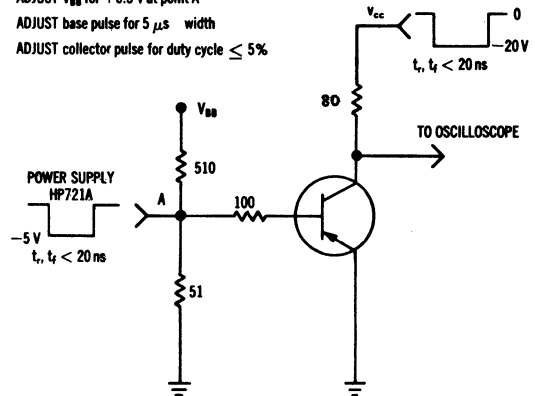
MAXIMUM RATINGS $(T_A = 25^\circ\text{C}$ unless otherwise noted)

Rating	Symbol	Value	Units
Collector-Base Voltage	V_{CB}	25	Vdc
Collector-Emitter Voltage	V_{CEO}	15	Vdc
Emitter-Base Voltage	V_{EB}	3.0	Vdc
Collector Current (Continuous)	I_C	300	mAdc
Junction Temperature	T_J	100	$^\circ\text{C}$
Storage Temperature	T_{stg}	-65 to +100	$^\circ\text{C}$
Device Dissipation @ 25°C Case Temperature (Derate 10 mW/ $^\circ\text{C}$ above 25°C)	P_D	750	mW
Device Dissipation @ 25°C Ambient (Derate 4 mW/ $^\circ\text{C}$)	P_D	300	mW

COLLECTOR LATCH-UP VOLTAGE AND TEST CIRCUIT



ADJUST V_{BB} for +0.5 V at point A
 ADJUST base pulse for 5 μs width
 ADJUST collector pulse for duty cycle $\leq 5\%$

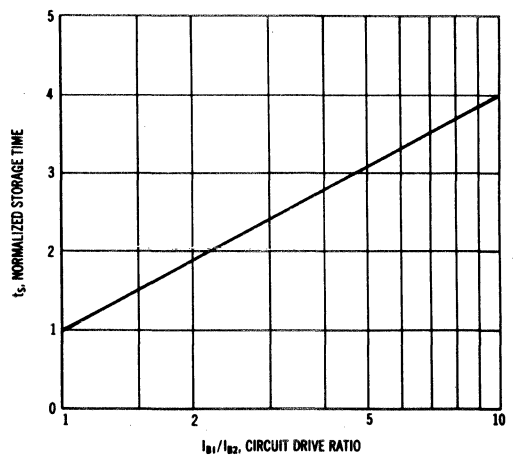
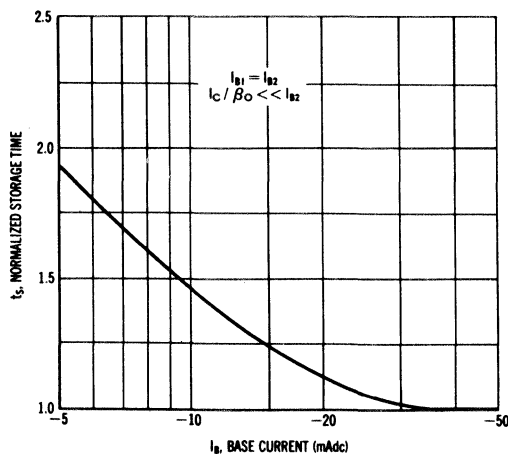


2N3883 (continued)

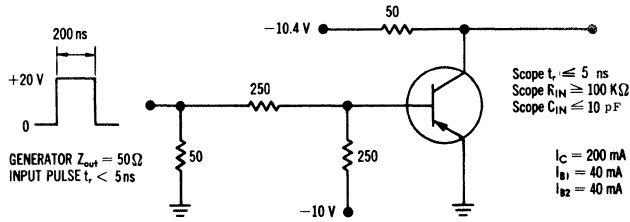
ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Collector-Base Breakdown Voltage ($I_C = 100\mu\text{Adc}$, $I_E = 0$)	BV_{CBO}	25	—	—	Vdc
Collector-Emitter Breakdown Voltage ($I_C = 10\text{mAdc}$, $I_B = 0$)	BV_{CEO}	15	—	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 100\mu\text{Adc}$, $I_C = 0$)	BV_{EBO}	3.0	—	—	Vdc
Latch-Up Voltage	LV_{CEX}	20	—	—	Vdc
Collector-Emitter Leakage Current ($V_{CE} = 15\text{Vdc}$, $V_{EB} = 0$)	I_{CES}	—	—	100	μAdc
Base Cutoff Current ($V_{CE} = 15\text{Vdc}$, $V_{EB} = 0$)	I_B	—	—	100	μAdc
DC Current Gain ($I_C = 20\text{C mAdc}$, $V_{CE} = 1.0\text{Vdc}$)	h_{FE}	30	—	—	—
Collector-Emitter Saturation Voltage ($I_C = 200\text{ mAdc}$, $I_B = 40\text{ mAdc}$)	$V_{CE(sat)}$	—	0.35	0.5	Vdc
Base-Emitter Voltage ($I_C = 200\text{ mAdc}$, $I_B = 40\text{ mAdc}$)	V_{BE}	0.4	0.65	0.9	Vdc
Output Capacitance ($V_{CB} = 10\text{Vdc}$, $I_E = 0$, $f = 100\text{ kHz}$)	C_{ob}	—	4.5	8.0	pF
Input Capacitance ($V_{BE} = 1\text{Vdc}$, $I_C = 0$, $f = 100\text{ kHz}$)	C_{ib}	—	10	25	pF
Current-Gain - Bandwidth Product ($V_{CE} = 10\text{Vdc}$, $I_C = 40\text{ mAdc}$, $f = 100\text{ MHz}$)	f_T	100	300	—	MHz
Delay Time	t_d	—	8.0	15	ns
Rise Time	t_r	—	28	40	ns
Storage Time	t_s	—	40	70	ns
Fall Time	t_f	—	28	40	ns

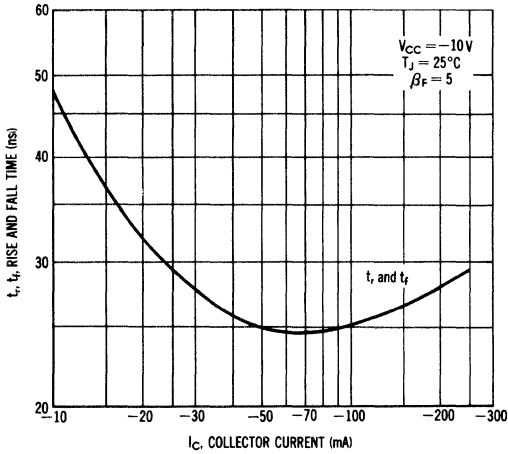
STORAGE TIME VARIATIONS



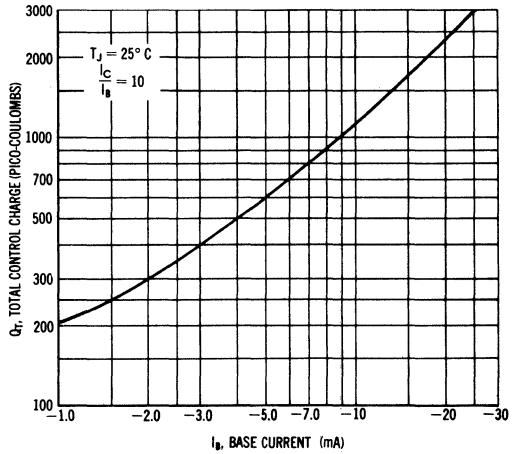
SWITCHING TIME TEST CIRCUIT



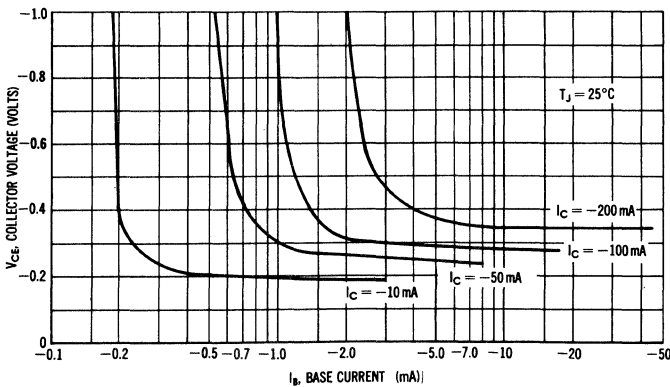
TYPICAL RISE AND FALL TIME BEHAVIOR



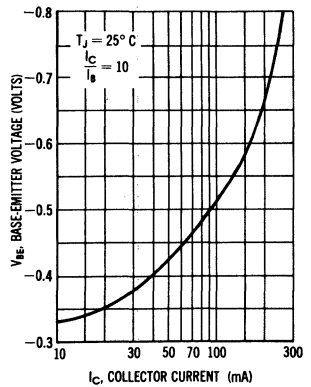
TOTAL CONTROL CHARGE



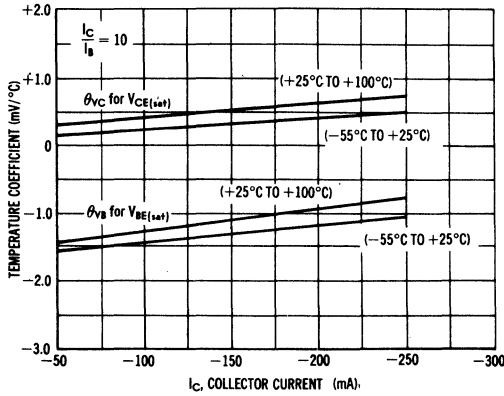
COLLECTOR-EMITTER SATURATION VOLTAGES versus BASE CURRENT



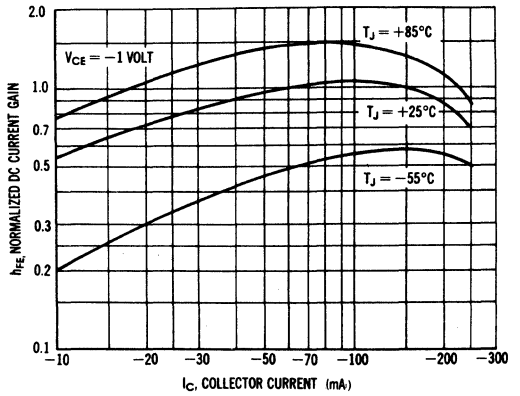
BASE-EMITTER VOLTAGE versus COLLECTOR CURRENT



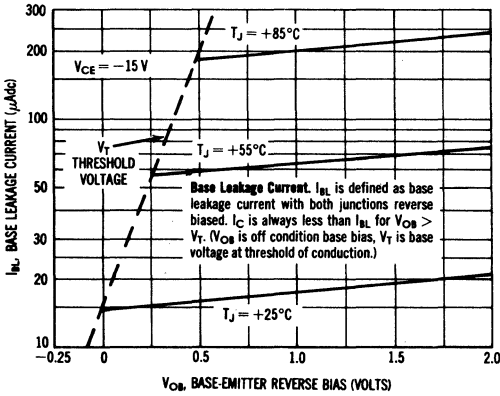
TEMPERATURE COEFFICIENTS



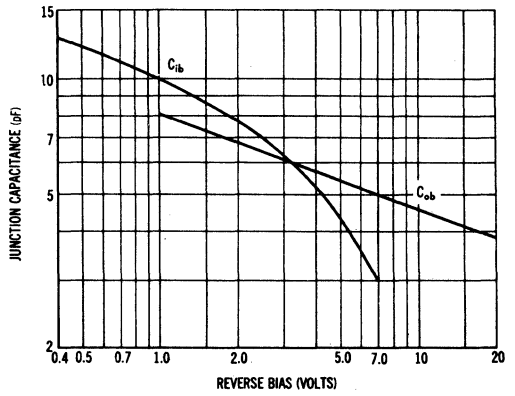
NORMALIZED CURRENT GAIN CHARACTERISTICS



LEAKAGE CHARACTERISTICS COMMON EMITTER



JUNCTION CAPACITANCE versus REVERSE VOLTAGE



2N3896 thru 2N3899 (SILICON)

For Specifications, See 2N3870 Data